

A Tunable Echelle Imager

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ABSTRACT

We describe and evaluate a new instrument design called a Tunable Echelle Imager (TEI). In this instrument, the output from an imaging Fabry-Perot interferometer is cross-dispersed by a grism in one direction and dispersed by an echelle grating in the perpendicular direction. This forms a mosaic of different narrow-band images of the same field on a detector. It offers a distinct wavelength multiplex advantage over a traditional imaging Fabry-Perot device.

Potential applications of the TEI include spectrophotometric imaging and OH-suppressed imaging by rejection.

Subject headings: techniques: interferometric, miscellaneous, photometric, spectroscopic

1. Introduction

One of the most versatile instruments for astronomical narrow-band imaging is the gap-scanning Fabry-Perot (FP) etalon. Light passing through a FP produces a series of wavelength passbands called orders (examples of the transmission are shown in Figure 1). The positions of the passbands can be moved by varying the separation of the cavity surfaces (e.g., Atherton et al. 1981; Atherton 1995; Bland-Hawthorn & Jones 1998). However, in order to image a field with a FP, broad- or intermediate-band filters are usually used to block out the light from all the passbands except the one of interest. An alternative method is to use a dispersive element to separate the images formed by different FP orders. Recently this principle has been used in the PYTHEAS instrument (le Coarer et al. 1995) and the GraF instrument (Chalabaev & le Coarer 1995; Chalabaev et al. 1999a, 1999b). In this paper, we consider the use of a cross-dispersed echelle grating¹ crossed with a gap-scanning FP called a Tunable Echelle Im-

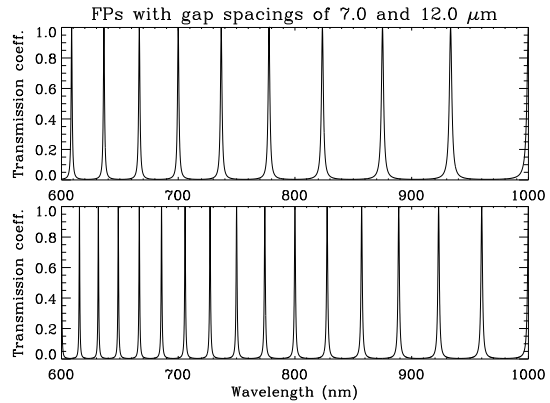


Fig. 1.— Transmission profiles for Fabry-Perot filters with two different gap spacings. The upper plot shows orders from 14 on the right to 23 on the left; the lower plot shows orders 24 to 40.

¹We use the term ‘echelle’ for any multi-order diffraction grating used above about the fifth order, rather than distinguishing between an ‘echellette’ and an ‘echelle’ grating.

ager (TEI). This forms a mosaic of narrow-band images with different wavelengths on a detector, and by scanning the plate separation of the FP, a complete data cube can be obtained (2D image plus 1D spectral).

1.1. The basic physics

The wavelength positions of the FP orders are described by the equation for constructive interference:²

$$m_{\text{fp}}\lambda = 2\mu d \cos \theta, \quad (1)$$

where m_{fp} is the FP order, μ is the refractive index of the medium in the cavity gap, d is the plate separation (or gap spacing) and θ is the angle of incidence.

The bandwidth of each FP order is dependent on the reflectivity and defects of the coated surfaces (non-parallelism). The ratio between inter-order wavelength spacing ($\Delta\lambda$) and the FWHM bandwidth ($\delta\lambda$) is called the effective finesse:

$$N = \frac{\Delta\lambda}{\delta\lambda}. \quad (2)$$

The finesse is also related to the contrast between the peak transmission of an order and the minimum transmission between orders. For contrast values greater than 100, 250, 500 or 1000, the finesse needs to be greater than 16, 25, 35 or 50, respectively. At high finesse, the efficiency can drop significantly due to defects (Atherton et al. 1981). A finesse between 20 and 40 is optimal for a high-throughput imaging FP (Bland-Hawthorn 1995).

The echelle grating (EG) disperses the FP orders using multi-order diffraction. The diffracted angle (β) for gratings that are not immersed between prisms is determined from the grating equation:

$$m_{\text{eg}}\lambda = \mu\Lambda(\sin \alpha + \sin \beta), \quad (3)$$

where m_{eg} is the EG order, μ is the refractive index of air, Λ is the grating period and α is the incidence angle in air.

With an echelle grating, several wavelengths corresponding to different EG orders are diffracted

at or near the same angle. For this reason, a low-dispersion element is needed to separate the EG orders. This could be another grating, one or more prisms, or a grism.

2. TEI setup

A TEI system is suitable for use at Cassegrain focus with a small collimated beam, preferably less than 100 mm in diameter for cheaper and better-quality etalons.

An aperture is placed in the telescope focal plane in order to prevent overlap of images at the detector. The TEI is placed in the collimated beam. Different setups are shown in Figures 2, 3 and 4.

The first optical element is the Fabry-Perot (FP) filter which produces a series of narrow pass-bands or orders. Alternatively, it is possible to put one or both of the dispersing elements before the FP. The advantage in placing the FP first is that all the light from a given point source passes through the FP at the same angle (θ). This allows for a smaller etalon and the variations in central wavelength across a field are the same for all orders (consider the $\cos \theta$ factor in Equation 1). If the variation in θ is small enough, the image of each field will be effectively monochromatic. For monochromaticity, it is preferable that the centre of the field is on-axis with the FP, i.e., to minimize the variation in $\cos \theta$.

The second optical element is a grism which separates the FP orders with low-dispersion first-order diffraction. In principal, a grating without a prism could be used. The advantage of using a grism is that it is more likely to be compatible with existing astronomical optical instruments if the beam is not deviated significantly at this point. Some grism formats are shown in Figure 5. In some cases, it may be necessary to include a colored-glass filter to block second- and higher-order diffraction by the grism. This could be placed before the FP element to minimize scattered light in the TEI.

The third optical element disperses the light in the perpendicular direction (to the grism) with high-dispersion multi-order diffraction. The dispersion is too high to correct to zero beam deviation by using a prism. The setup in Figure 2 uses a transmission grating with Littrow diffraction. The

²Note that Equation 1 does not include the effect of phase changes on reflection (Atherton et al. 1981; Jones & Bland-Hawthorn 1998). Such phase changes only have a significant impact for low-order etalons which are not considered here.

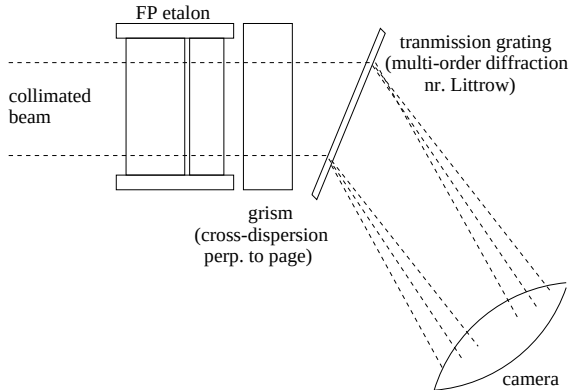


Fig. 2.— TEI with a transmission echelle grating. The grism disperses the FP orders perpendicular to the page. The echelle grating disperses the light near Littrow thus preserving the aspect ratio of the field on the detector. The many orders of the echelle allow a mosaic of images to be formed.

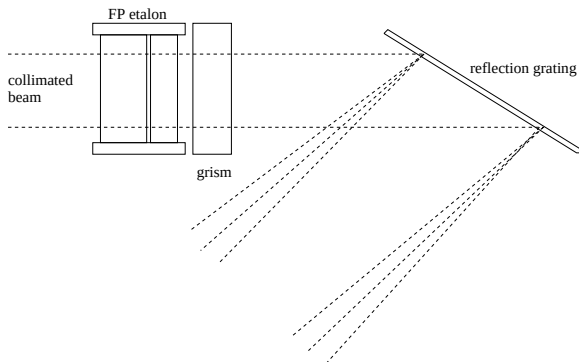


Fig. 3.— TEI with a reflection echelle grating (blaze to collimator). In this case, the echelle grating expands the beam.

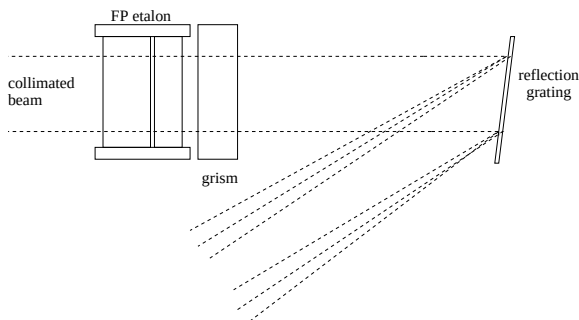


Fig. 4.— TEI with a reflection echelle grating (blaze to camera). In this case, the echelle grating reduces the size of the beam.

advantage of this is that the beam size remains the same after diffraction and, therefore, the pixel scale on the detector is the same as for direct imaging. The setup in Figure 3 uses a reflection grating. Higher spectral resolution (or a larger field for a given resolution) can be achieved with this setup but there is an anamorphic increase in beam size. An alternative reflection grating setup is shown in Figure 4 with an anamorphic decrease in beam size. In this case, it may be advantageous to place the grism after the reflection grating.

The use of an articulated camera³ would allow a choice of the beam deviation that is most suitable for the experiment. Especially in the case of the transmission echelle grating, the ability to control the observed angle of diffraction allows significant control over the dispersion and anamorphic factor of the instrument. The recent advent of volume-phase holographic (VPH) technology offers another advantage for the completely transmissive version of the TEI, in that, the grism and echelle grating could be combined into one optical element for higher efficiency (a multiplexed grating; Barden et al. 2000).

2.1. Parameters

There are a number of different parameters that define the properties of the instrument. The principal parameters that we will consider are:

- for the telescope:
 - the field-of-view size,
 - the beam reduction factor (collimated-beam diameter / telescope diameter = $f_{\text{coll}}/f_{\text{tel}}$), which determines the scaling between angles in the collimated beam and on the sky;
- for the Fabry-Perot filter:
 - the separation between the highly reflective surfaces of the FP (d), which determines the central wavelengths of the orders and the separations between the orders,

³For example, articulated cameras are planned for the ATLAS (Robertson et al. 2000) and OSIRIS (Cepa et al. 2000) spectrographs.

- the finesse (N), which determines the resolution and contrast for a given order;
- for the echelle grating:
 - the line density of the grating ($1/\Lambda$),
 - the incident and diffracted angles (α and β).
- for the grism:
 - the line density of the grating,
 - the angle and the refractive index of the prism(s),
 - the incident and diffracted angles;

In the next section (2.2), we give some examples of various setup parameters.

2.2. Examples

To determine the type of images that can be obtained with a TEI, we shall consider a system that can image a $12^\circ \times 12^\circ$ angular spread in the collimated beam. This corresponds to a 6×6 arcminute field of view for a telescope with a beam reduction factor of $1/120$ (e.g., a 10-m telescope with an 83-mm collimated beam), or a 12×12 arcminute view with a beam reduction factor of $1/60$ (e.g., a 4-m telescope with a 67-mm beam). For the 6×6 arcminute field, the image sampling corresponds to 0.18 arcsec per pixel for a $2K \times 2K$ detector.

Examples of various setup parameters are shown in Table 1. The fixed grism format disperses the wavelength range 600 to 1000 nm across the detector with first-order diffraction. For most optical systems, a colored filter would be required to block wavelengths below 500 nm (e.g., OG 550) to avoid contamination of the images with second-order diffraction from the grism. This range was chosen to span roughly an octave in spectral coverage. The TEI setup parameters can easily be adapted for other wavelength ranges, beam characteristics and detector sizes.

The plate separation of the FP determines the number of imaged orders between 600 and 1000 nm. This combined with the finesse determines the resolving power of the instrument. If the finesse is constant across the observed wavelengths then the resolving power will be highest

at the shortest wavelength and be proportional to $1/\lambda$. This could be altered by increasing the reflectivity as a function of wavelength.

The parameters of the echelle grating determine the maximum aperture size usable at a given resolving power (without overlap of FP orders). Higher dispersion gratings and/or increased anamorphic factor allow for wider apertures or a larger resolving power. The maximum length of the aperture is determined by the separation of the EG orders imaged onto the detector. Simulated images of FP orders with various EG orders and dispersions (Table 1) are shown in Figures 6–11.

3. Discussion

3.1. Observing and data reduction

To fully sample the spectral dimension at the resolving power of the TEI setup, it will be necessary to take a number of exposures (at different FP gap spacings) equal to or greater than the finesse of the FP. The reason for a greater number of exposures is because the requirements for sampling at the shortest wavelength may be different from the longest wavelength. In many cases, there will be double sampling of some wavelengths near the shortest wavelength, these could be used as a self-calibration check in reconstructing the spectral dimension.⁴ Spectrophotometric measurements could be obtained in photometric conditions by calibrating with a standard star.

The TEI can mimic a true 3D spectrograph by scanning, as described above. Some applications may not need scanning or only partial scanning (a few exposures) if the sampling of the spectral dimension is adequate. For example, multiple narrow-band imaging could be used to selectively combine images in order to suppress sky-emission lines, thus mimicking an OH-suppression instrument.

Wavelength calibration of a TEI would be made using arc lamps to define the wavelength for each order and gap spacing for the etalon. The calibration is then uniquely defined for a given gap spacing and should be stable during an exposure

⁴Bland & Tully (1989) noted that it was easier to reconstruct the λ dimension than an image dimension (e.g., as with a scanning slit or IFU).

Table 1: Examples of various setup parameters for a TEI

Aperture	Fabry-Perot parameters			Echelle-grating parameters					Fig.	
Field size ^a (arcsec)	Plate sep. (μm)	Res. ^b at 600 nm	No. ^c of orders	Type	Line d. (mm^{-1})	Inc. angle	Diff. ^d angle	Anamor. factor	No. ^e of orders	
48 x 38	12	1200	17	trans.	145	25°	25°	1.00	5	6
39 x 23	27	2700	37	trans.	145	32°	32°	1.00	6	7
39 x 14	45	4500	61	trans.	145	32°	32°	1.00	6	—
19 x 11	80	8000	107	trans.	90	40°	40°	1.00	11	8
20 x 9	80	8000	107	reflec.	90	25°	55°	0.63	10	9
20 x 14	80	8000	107	reflec.	90	55°	25°	1.58	10	10
12 x 6	190	19000	254	reflec.	70	43°	63°	0.62	16	11
12 x 6	310	31000	414	reflec.	70	63°	43°	1.61	16	—
15 x 4	900	90000	1201	reflec.	100	75°	55°	2.22	13	—

Note: all the examples use a grism (type-A format, 410lines/mm, 29°-prism, $n_{\text{prism}} = 1.67$) which gives zero deviation at a wavelength of 800 nm with first-order diffraction. For the reflection echelle gratings, the angle between camera and collimator is 20° or 30°.

^aThe field size chosen to match the setup with no overlap of imaged FP orders, assuming a beam reduction factor of 1/120 (e.g., a 10-m telescope with an 83-mm collimated beam). For a beam reduction factor of 1/60 (e.g., a 4-m telescope with a 67-mm beam), the field dimensions are doubled.

^bThe resolving power ($\lambda/\delta\lambda$) at 600 nm, assuming a finesse of 30, $\theta = 0$ and $\mu = 1$ for the FP.

^cThe number of FP orders between 600 and 1000 nm.

^dThe diffracted angle required to image on the central axis of the detector (ideally peak efficiency).

^eThe number of useful EG orders for the wavelengths between 600 and 1000 nm.

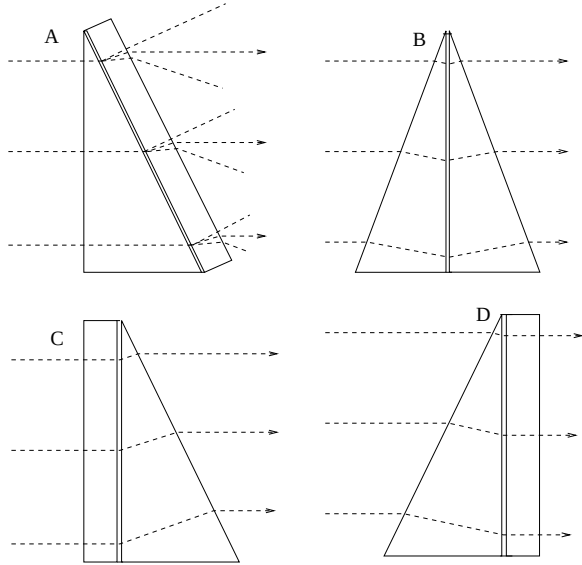


Fig. 5.— Examples of grism formats. With A- and B-type formats, the beam remains the same size for zero deviation light. The C-type format reduces the size of the beam while the D-type format expands the beam slightly.

using capacitance micrometry (Hicks et al. 1984). Advantageously, the spectral stability of the TEI is not subject to instrument flexure as with a normal Cassegrain spectrograph.

In some of the example image formats, it appears that optimal use is not made of the detector in the sense that there are repeated orders (e.g., Figure 10). However, if every order is repeated twice on the detector, it may increase the efficiency and allow the possibility of removing image defects (e.g., hot pixels, cosmic rays, bad columns) by comparing the same narrow-band image.

3.2. Aperture width and the PSF

The dispersion of the gratings spreads out the light from a single FP order, contributing to the point spread function (PSF) of the image. The FWHM of this one-dimensional contribution is equal to the separation (on the detector) between adjacent FP orders divided by the finesse. The lines in the bottom-left corner of each image in the Figures 6–11 represent this PSF.

If the aperture size is maximized for a particu-

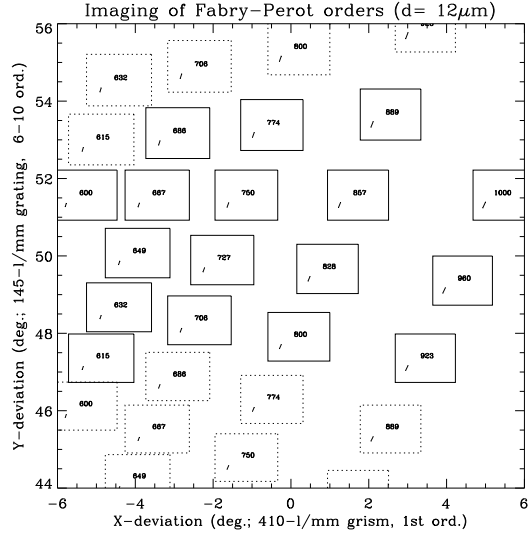


Fig. 6.— Mosaic of images produced by a TEL. The angles relate to deviations within the collimated beam (not to angles on the sky). The central wavelengths in nanometres of each narrow-band image are shown within each square. Images shown with dashed lines are repeated FP orders. The line in the bottom-left corner of each image is the PSF caused by the dispersion.

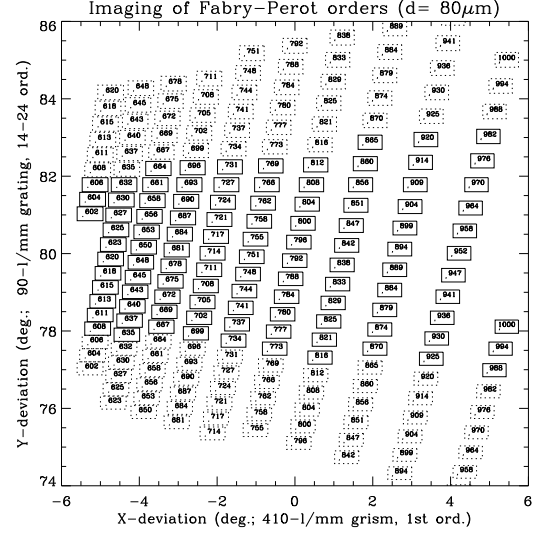


Fig. 8.— Mosaic of images produced by a TEL.

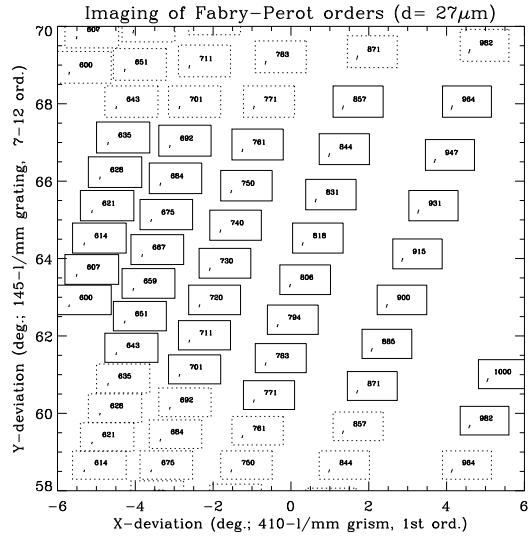


Fig. 7.— Mosaic of images produced by a TEL.

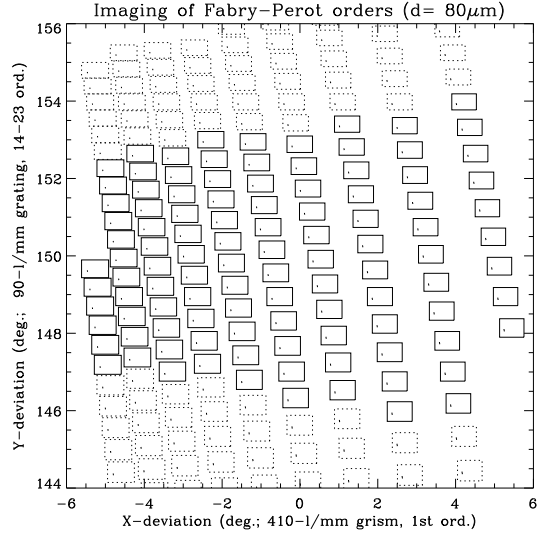


Fig. 9.— Mosaic of images produced by a TEL.

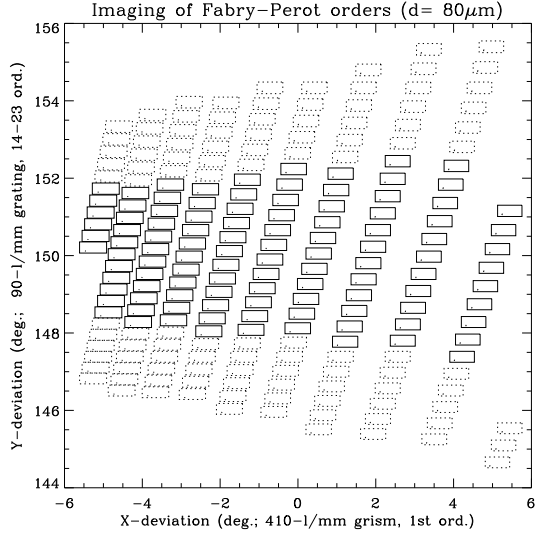


Fig. 10.— Mosaic of images produced by a TEI.

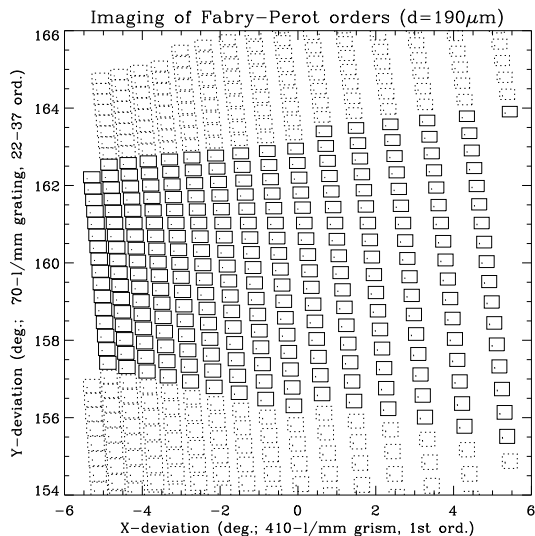


Fig. 11.— Mosaic of images produced by a TEI.

lar echelle grating and FP setup then the FWHM of the dispersive PSF is equal to the width of the aperture divided by the finesse, for the lowest wavelength. Therefore, if a certain image resolution is required in both spatial dimensions (the TEI only degrades resolution in one direction), then there is a limit on the setups to those with certain aperture widths. For example, in the case of adaptive optics a resolution of 0.1 arcsec may be required limiting the aperture width to 3 arcsec (with a finesse of 30). Alternatively, if 0.5 arcsec is satisfactory then an aperture width of 15 arcsec would be suitable. If good image resolution is only required in one direction then the aperture width can be larger still.

We note that the elongated PSF is a common occurrence in radio interferometry where many software tools exist to treat such data (Perley et al. 1994). The TEI situation is somewhat better because an instrument rotation allows us to sample the field with orthogonal PSF orientations.

3.3. Anamorphic factor

The ratio of the beam sizes after and before diffraction by a grating is called the anamorphic factor. For a reflection grating or a transmission grating without prisms, the anamorphic factor

$$A = \frac{\cos \beta}{\cos \alpha}, \quad (4)$$

where α and β are the incident and diffracted angles in air. The change in beam size is inverse to the change in angular size (the angle between light rays in the collimated beam). A grating setup which has an anamorphic factor above unity can increase the resolution because the angular size of the aperture (in the dispersion direction) is reduced. However, the increase in resolution is less than the anamorphic factor because the dispersion is also reduced (though not by as much).

Figures 9 to 10 show the effect of varying the anamorphic factor with the same resolution and EG orders (see Table 1). Larger apertures can be used with the blaze-to-collimator setup (increasing beam size) even though the images appear smaller on the detector (Fig. 10). Using the example of a 2K x 2K CCD and a 6 x 6 arcminute field, the pixel sampling on the detector would change from 0.18 to 0.28 arcsec/pixel across the width of the aperture (14 arcsec). The change in sampling is not

critical in this case because the dispersion PSF is about 0.47 arcsec (FWHM). In quadrature with 0.5 arcsec seeing, we find that the sampling is still adequate. In other cases a large anamorphic factor could cause undersampling of the PSF (instrumental and seeing) on the detector. Ideally, the change in sampling caused by an increase in beam size could be matched to the decrease in image resolution. A decrease in beam size cannot cause undersampling on the detector.

With a limited number of gratings, it would be useful to be able to use either a transmission or a reflection grating setup, with an increase or decrease in beam size. In this way, the aperture width could be matched more easily to the desired spectral resolving power.

A decrease or no change in beam size after dispersion has the advantage of instrumental compactness, in that, the camera optics could be smaller than if an increase in beam size is allowed.

3.4. Finesse

Choosing the finesse is tradeoff between a number of factors. A lower finesse has the advantage of needing less scans to complete the data cube. In effect, the total throughput of the instrument is approximately proportional to $1/N$. A higher finesse has the advantage of higher spectral and image resolution, and better suppression of the light between the narrow bands.

3.5. Comparison with a mono-order FP

The advantages of the TEI over a FP, where a single order has been selected with a blocking filter, include: imaging in many narrow bands simultaneously, and; imaging at any wavelength and spectral resolution without the need for many order-sorter filters. The disadvantages include: a smaller field of view; compromised image resolution (in one direction) because of the PSF caused by the dispersion, and; efficiency loss for a single order due to the extra dispersive elements.

A significant aspect of the TEI is that the field, although smaller, will be monochromatic or nearly monochromatic in many cases. In fact, the size of the field decreases as the spectral resolving power (R) is increased which is in the same sense as the Jacquinot (1954, 1960) criterion for a monochro-

matic field:

$$R \Omega = 2\pi, \quad (5)$$

where Ω is the solid angle at the FP. The TEI parameters can be chosen to give maximum spectral coverage for the monochromatic field.

3.6. Comparison with the GraF concept

The GraF concept uses a single dispersive element to separate the FP orders (Chalabaev & le Coarer 1995). Such a concept has been used in the GRAF/ADONIS instrument on the ESO 3.6-m telescope (Chalabaev et al. 1999a, 1999b). This instrument operates in the near-IR with adaptive optics used to obtain 0.1 arcsec image resolution. As an example, it can provide 10 images of 9" by 0.9" in the H band at a spectral resolution of 10000 (Chalabaev et al. 1999b). The field is thus small and narrow for high image resolution.

Here, we compare the TEI with a more general GraF instrument. A lower image resolution GraF instrument could, for example, have a field of 6 arcmin by 20 arcsec.

The advantage of the TEI is the ability to image in more FP orders simultaneously, i.e., providing a larger wavelength coverage except for the lowest spectral resolutions. The disadvantages include: efficiency losses due to the extra dispersive element, and; a shorter field of view.

In general, the shorter field of view is not a significant disadvantage because (i) the field will not be monochromatic over a longer field of view and (ii) astrophysical objects of interest may not be extended in one direction only, over the length of field possible with a GraF instrument (arcminutes).

The TEI could be converted to a GraF instrument by replacing the echelle grating with a mirror, or positioning the camera for direct imaging.

3.7. Comparison with an echelle grating

The advantages of the TEI over a standard echelle grating include: imaging, and; better spectrophotometry because a wider aperture can be used without compromising wavelength calibration or resolution. A disadvantage is that it requires scanning (tens of exposures) to fully sample a wavelength region.

The TEI can reach the same resolution as a

standard echelle with a wider aperture and a smaller beam. The first factor allows better sampling of extended sources and the second allows the TEI to be a Cassegrain instrument with a smaller camera. These two factors partially offset the disadvantage of the scanning requirement in terms of efficiency. In certain cases, the TEI could be comparable to a slit echelle spectrograph for high-resolution spectroscopy of extended sources. For spectrophotometry and imaging, the TEI is significantly better.

3.8. Comparison with an IFS

In recent years, there has been great interest in the use of integral-field spectrographs (IFS). These include image slicers (e.g., Content 2000), integral-field units and the TIGER approach (Courtès 1982; Courtès et al. 1988; Bacon et al. 1995). Both TEI and IFS instruments are true 3D spectrographs. However, they differ in one key respect. For the IFS, the incident wavefront is divided and dispersed, in contrast to the TEI where the wavefront is only dispersed.

The advantages of the TEI compared to an IFS include: better imaging and spectrophotometry because images do not need to be reconstructed; a larger field of view for a given detector size, and; potentially higher spectral resolution. The disadvantages include: the scanning requirement to fully sample a wavelength region, and; compromised image resolution (in one direction) because of the PSF.

Integral-field spectrographs divide the focal plane and therefore image integrity can be compromised (i.e., they are not spectrophotometric). So while an IFU is more efficient than a TEI device, for the same image size and spectral resolution requirements, there are certain cases where the TEI's undivided approach to 3D spectro-imaging could be more beneficial.

3.9. Some applications

The potential applications include: spectro-imaging and/or high-resolution spectroscopy of extended sources, through production of a full data cube; OH suppression in the 600–1600 nm wavelength range (*RIzJH*), and; targeted line imaging.

The OH-suppression method is to selectively

combine the images produced by a TEI, rejecting those images that contain OH-line emission (or applying a lower weight). This will considerably reduce the sky background especially in the *J* and *H* bands. Figure 12 shows an example of a FP transmission profile plotted over the *J*-band sky emission spectrum.

Evaluation of OH-suppression methods has been done by Herbst (1994); Jones et al. (1996); Offer & Bland-Hawthorn (1998). Equation 5 of Jones et al. gives the gain (G) in performance of an OH-suppression filter for the broad-band S/N.⁵ For background limited conditions, this equation reduces to

$$G = \frac{\tau}{\sqrt{\beta}}, \quad (6)$$

where τ is the fraction of object flux remaining, and β is the fraction of background remaining. Simple numerical calculations, for the broad-band S/N in the *J* band, show that G can be larger or about unity, when selectively combining TEI images at resolving powers of above 10000 using a finesse of 30. Note that this broad-band gain only applies to dark time because the TEI is imaging between the OH lines where the background flux is moon-phase dependent. Additionally, a suitable TEI instrument could image in the *J* and *H* bands simultaneously and provide a spectrum (low-resolution if the FP is not scanned).

As with a mono-order FP, the TEI could be used for targeted line imaging but, in addition, the TEI can simultaneously provide an OH-suppressed broad-band image using the non-targeted FP orders. The reduction of field of view in comparison with a standard FP mode is not always significant because, if the FP is not scanned, it is only the monochromatic field of view that images the targeted emission line.

4. Summary

The Tunable Echelle Imager offers an interesting reformation of existing spectrographs, by the use of a Fabry-Perot filter crossed with an echelle

⁵The analysis of Jones et al. (1996) uses Poisson-noise statistics. They point out that even $G \sim 1$ could provide a significant S/N gain, if most of the OH emission is removed from the background, because the continuum background is more stable and therefore systematic effects could be reduced.

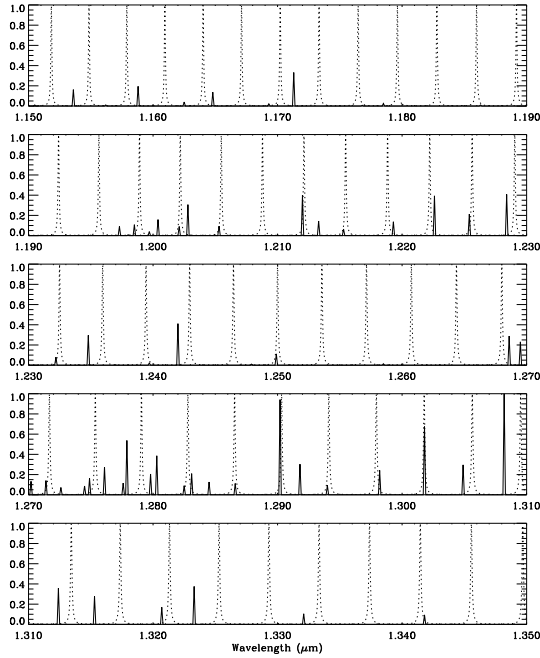


Fig. 12.— Plots of the transmission profile of a FP (dotted line) with a gap spacing of $220\ \mu\text{m}$ and a finesse of 30, and an OH sky emission spectrum (solid line), in the *J* band. The TEI images produced by the different FP orders can be combined selectively to exclude most of the OH emission. The sky emission spectrum is the same as that used by Offer & Bland-Hawthorn (1998).

grating. This forms a mosaic of narrow-band images on a detector, offering a significant multiplex wavelength advantage over a mono-order FP system.

The TEI instrument is placed in the collimated beam and includes a FP element, a grism and an echelle grating. Parameters such as the plate separation of the FP and the dispersion of the echelle determine the resolving power and the field-of-view size of the images. Resolving powers ranging from about 1000 to 100 000 are observable with fields of view ranging from an arcminute down to arcseconds in size.

The potential of the TEI includes its spectrophotometric integrity for producing a 3D datacube and the ability to create an OH-suppressed image by selectively combining different FP orders.

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